

● PRINTER RUSH ●

(PTO ASSISTANCE)

2nd request

Application : 101658479

Examiner : Trinh

GAU : 2814

From: J. Black

Location: IDC FMF FDC

Date: 6/13/05

Tracking #: D6084781

Week Date: 12/20/04

DOC CODE	DOC DATE	MISCELLANEOUS
<input type="checkbox"/> 1449		<input type="checkbox"/> Continuing Data
<input type="checkbox"/> IDS		<input type="checkbox"/> Foreign Priority
<input type="checkbox"/> CLM		<input type="checkbox"/> Document Legibility
<input type="checkbox"/> IIFW		<input type="checkbox"/> Fees
<input type="checkbox"/> SRFW		<input type="checkbox"/> Other
<input checked="" type="checkbox"/> DRW	<u>4/15/05</u>	
<input type="checkbox"/> OATH		
<input type="checkbox"/> 312		
<input type="checkbox"/> SPEC		

Attn Chief Draftsperson:

[RUSH] MESSAGE:

Figures 1, 2 and 3 contain crossed-out and
handwritten data.

Please resolve.

[XRUSH] RESPONSE:

CORRECTED DRAWINGS

RESOLVED

ATTACHED

6-21-2005

E

INITIALS

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NOTE: This form will be included as part of the official USPTO record, with the Response document coded as XRUSH.

REV 10/04

STRAINED SILICON
IMPROVED THERMAL CONDUCTIVITY AND
METHOD FOR ITS FABRICATION
Invention: Jung-Suk Goo et al.
Attorney: Ronald Costick - 039153-0676
FOLEY & LARDNER - (310) 277-2213
Sheet 1 of 7

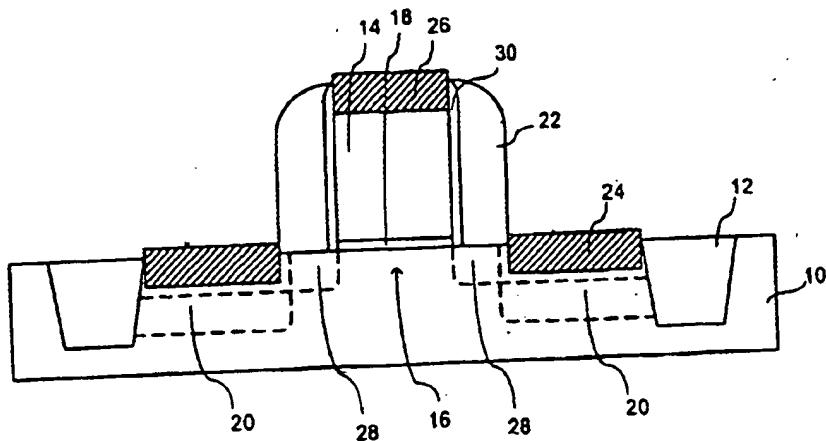


Figure 1
Prior Art

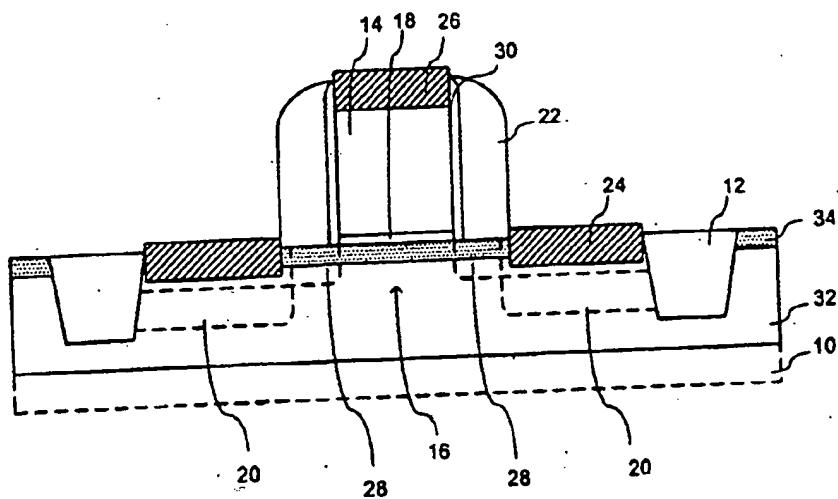


Figure 2
Prior Art

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11
STRAINED SILICON MOSFET HAVING
IMPROVED THERMAL CONDUCTIVITY AND
METHOD FOR ITS FABRICATION
Inventors: Jang-Suk Goo et al.
Attorney: Ronald Costick - 039153-0676
FOLEY & LARDNER - (310) 277-1222
Sheet 2 of 7

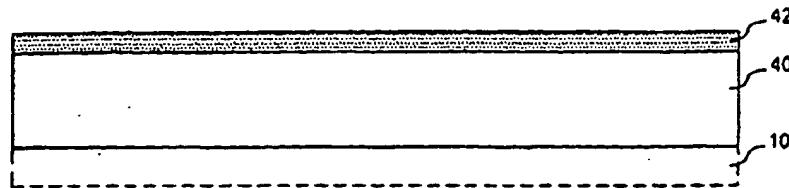


Figure 3a

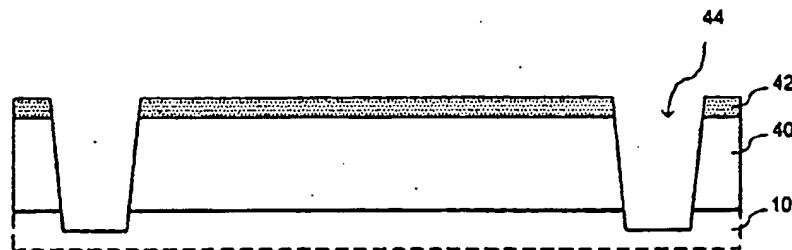


Figure 3b

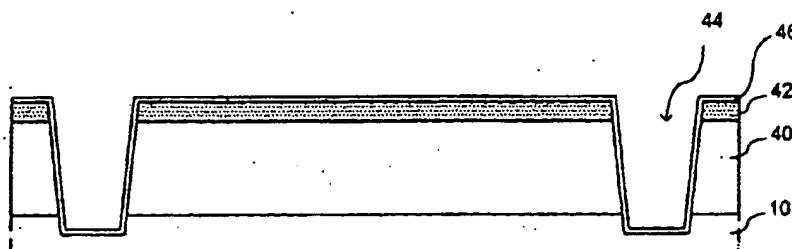


Figure 3c

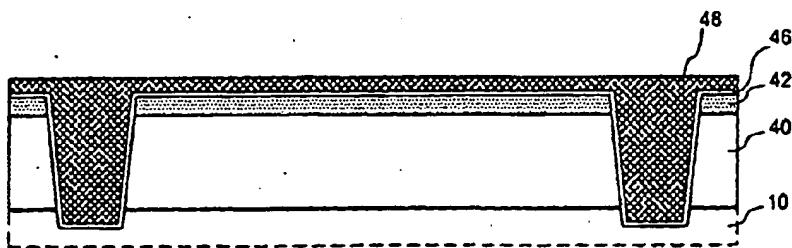


Figure 3d

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